



## General description

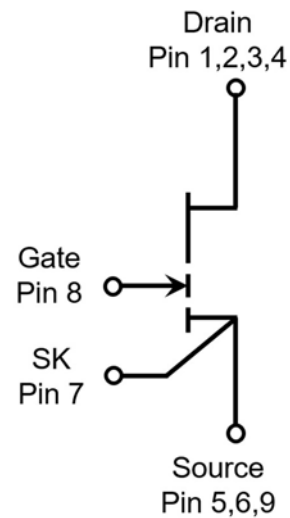
650V GaN-on-Silicon Enhancement-mode  
Power Transistor in Dual Flat No-lead  
Package (DFN) with 8 mm × 8 mm size.

## Features

- Enhancement-mode transistor - normally-OFF power switch
- Ultra-high switching frequency
- No reverse-recovery charge
- Low gate charge, low output charge
- Qualified for industrial applications according to JEDEC Standards
- ESD safeguard
- RoHS, Pb-free, REACH-compliant

## Applications

- AC-DC converters
- DC-DC converters
- Totem pole PFC
- Fast battery charging
- High-density power conversion
- High-efficiency power conversion



|               |            |
|---------------|------------|
| Gate          | 8          |
| Drain         | 1, 2, 3, 4 |
| Kelvin Source | 7          |
| Source        | 5, 6, 9    |



## Maximum ratings

at  $T_j = 25\text{ °C}$  unless otherwise specified. Continuous application of maximum ratings can deteriorate transistor lifetime. For further information, contact CloudSemi sales office.

**Table 3 Maximum rating**

| Parameters                                   | Symbols             | Values |      |      | Units | Notes/Test Conditions   |
|--|---------------------|--------|------|------|-------|---|
|  |                     | Min.   | Typ. | Max. |       |   |
| Drain-source voltage                         | $V_{DS, max}$       | -      | -    | 650  | V     | $V_{GS} = 0\text{ V}$ , $I_D = 10\text{ }\mu\text{A}$   |
| Drain-source voltage transient <sup>1</sup>  | $V_{DS, transient}$ | -      | -    | 750  | V     | $V_{GS} = 0\text{ V}$ , $V_{DS} = 750\text{ V}$   |
| Continuous current, drain-source             | $I_D$               | -      | -    | 10   | A     | $T_c = 25\text{ °C}$  |
| Pulsed current, drain-source <sup>2</sup>    | $I_{D, pulse}$      | -      | -    | 18   | A     | $T_c = 25\text{ °C}$ ; $V_G = 6\text{ V}$   |
| Pulsed current, drain-source <sup>2</sup>    | $I_{D, pulse}$      | -      | -    | 10   | A     | $T_c = 125\text{ °C}$ ; $V_G = 6\text{ V}$  |
| Gate-source voltage, continuous <sup>3</sup> | $V_{GS}$            | -1.4   | -    | +7   | V     | $T_j = -55\text{ °C}$ to $150\text{ °C}$  |
| Gate-source voltage, pulsed                  | $V_{GS, pulse}$     | -      | -    | +10  | V     | $T_j = -55\text{ °C}$ to $150\text{ °C}$ ;<br>$t_{Pulse} = 50\text{ ns}$ , $f = 100\text{ kHz}$ ;<br>open drain |
| Power dissipation                            | $P_{tot}$           | -      | -    | 75   | W     | $T_c = 25\text{ °C}$  |
| Operating temperature                        | $T_j$               | -55    | -    | +150 | °C    |   |
| Storage temperature                          | $T_{stg}$           | -55    | -    | +150 | °C    |   |

1.  $V_{DS, transient}$  is intended for surge rating during non-repetitive events,  $t_{Pulse} < 1\text{ }\mu\text{s}$ .

2. Pulse width =  $10\text{ }\mu\text{s}$ .

3. The minimum  $V_{GS}$  is clamped by ESD protection circuit, as shown in Figure 8.

## Thermal characteristics

**Table 4 Thermal characteristics**

| Parameters                        | Symbols    | Values |      |      | Units | Notes/Test Conditions |
|-----------------------------------|------------|--------|------|------|-------|-----------------------|
|                                   |            | Min.   | Typ. | Max. |       |                       |
| Thermal resistance, junction-case | $R_{thJC}$ | -      | -    | 1.65 | °C/W  |                       |
| Reflow soldering temperature      | $T_{sold}$ | -      | -    | 260  | °C    | MSL3                  |



## Electrical characteristics

at  $T_j = 25\text{ }^\circ\text{C}$ , unless specified otherwise.

**Table 5 Static characteristics**

| Parameters                       | Symbols      | Values |      |      | Units            | Notes/Test Conditions   |
|----------------------------------|--------------|--------|------|------|------------------|---|
|                                  |              | Min.   | Typ. | Max. |                  |   |
| Gate threshold voltage           | $V_{GS(TH)}$ | 1.2    | 1.6  | 2.5  | V                | $I_D = 11\text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 25\text{ }^\circ\text{C}$         |
|                                  |              | -      | 1.6  | -    |                  | $I_D = 11\text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 125\text{ }^\circ\text{C}$        |
| Drain-source leakage current     | $I_{DSS}$    | -      | 0.4  | 20   | $\mu\text{A}$    | $V_{DS} = 650\text{ V}$ ; $V_{GS} = 0\text{ V}$ ; $T_j = 25\text{ }^\circ\text{C}$  |
|                                  |              | -      | 4    | -    |                  | $V_{DS} = 650\text{ V}$ ; $V_{GS} = 0\text{ V}$ ; $T_j = 125\text{ }^\circ\text{C}$ |
| Gate-source leakage current      | $I_{GSS}$    | -      | -    | 200  | $\mu\text{A}$    | $V_{GS} = 6\text{ V}$ ; $V_{DS} = 0\text{ V}$                                       |
| Drain-source on-state resistance | $R_{DS(on)}$ | -      | 160  | 200  | $\text{m}\Omega$ | $V_{GS} = 6\text{ V}$ ; $I_D = 3\text{ A}$ ; $T_j = 25\text{ }^\circ\text{C}$       |
|                                  |              | -      | 330  | -    | $\text{m}\Omega$ | $V_{GS} = 6\text{ V}$ ; $I_D = 3\text{ A}$ ; $T_j = 125\text{ }^\circ\text{C}$      |
| Gate resistance                  | $R_G$        | -      | 3.5  | -    | $\Omega$         | $f = 5\text{ MHz}$ ; open drain   |

**Table 6 Dynamic characteristics**

| Parameters  | Symbols      | Values |      |      | Units | Notes/Test Conditions  |
|---|--------------|--------|------|------|-------|--|
|   |              | Min.   | Typ. | Max. |       |  |
| Input capacitance   | $C_{iss}$    | -      | 83   | -    | pF    | $V_{GS} = 0\text{ V}$ ; $V_{DS} = 400\text{ V}$ ; $f = 100\text{ kHz}$   |
| Output capacitance  | $C_{oss}$    | -      | 27   | -    | pF    | $V_{GS} = 0\text{ V}$ ; $V_{DS} = 400\text{ V}$ ; $f = 100\text{ kHz}$   |
| Reverse transfer capacitance                              | $C_{rss}$    | -      | 0.4  | -    | pF    | $V_{GS} = 0\text{ V}$ ; $V_{DS} = 400\text{ V}$ ; $f = 100\text{ kHz}$   |
| Effective output capacitance, energy related <sup>1</sup> | $C_{o(er)}$  | -      | 35   | -    | pF    | $V_{GS} = 0\text{ V}$ ; $V_{DS} = 0\text{ to }400\text{ V}$  |
| Effective output capacitance, time related <sup>2</sup>   | $C_{o(tr)}$  | -      | 54   | -    | pF    | $V_{GS} = 0\text{ V}$ ; $V_{DS} = 0\text{ to }400\text{ V}$  |
| Output charge   | $Q_{OSS}$    | -      | 22   | -    | nC    | $V_{GS} = 0\text{ V}$ ; $V_{DS} = 0\text{ to }400\text{ V}$  |
| Turn-on delay time  | $t_{d(on)}$  | -      | 2    | -    | ns    | $V_{DS} = 400\text{ V}$ ; $I_D = 6\text{ A}$ ; $L = 318\text{ }\mu\text{H}$ ;<br>$V_{GS} = 6\text{ V}$ ; $R_{on} = 10\text{ }\Omega$ ; $R_{off} = 2\text{ }\Omega$ |
| Turn-off delay time                                       | $t_{d(off)}$ | -      | 4    | -    | ns    |  |
| Rise time   | $t_r$        | -      | 5    | -    | ns    |  |
| Fall time   | $t_f$        | -      | 6    | -    | ns    |  |

1.  $C_{o(er)}$  is the fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 400 V.

2.  $C_{o(tr)}$  is the fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 400 V.



**Table 7 Gate charge characteristics**

| Parameters           | Symbols    | Values |      |      | Units | Notes/Test Conditions                                 |
|----------------------|------------|--------|------|------|-------|---|
|                      |            | Min.   | Typ. | Max. |       |   |
| Gate charge          | $Q_G$      | -      | 2.3  | -    | nC    | $V_{GS} = 0$ to 6 V; $V_{DS} = 400$ V;<br>$I_D = 3$ A |
| Gate-source charge   | $Q_{GS}$   | -      | 0.2  | -    | nC    |   |
| Gate-drain charge    | $Q_{GD}$   | -      | 0.9  | -    | nC    |   |
| Gate plateau voltage | $V_{Plat}$ | -      | 2.4  | -    | V     | $V_{DS} = 400$ V; $I_D = 3$ A                         |

**Table 8 Reverse conduction characteristics**

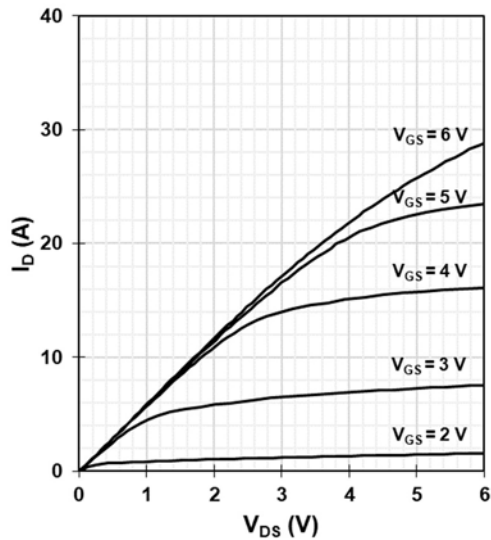
| Parameters                    | Symbols        | Values |      |      | Units | Notes/Test Conditions            |
|-------------------------------|----------------|--------|------|------|-------|----------------------------------|
|                               |                | Min.   | Typ. | Max. |       |                                  |
| Source-drain reverse voltage  | $V_{SD}$       | -      | 2.5  | -    | V     | $V_{GS} = 0$ V; $I_{SD} = 3$ A   |
| Pulsed current, reverse       | $I_{S, pulse}$ | -      | 20   | -    | A     | $V_{GS} = 6$ V                   |
| Reverse recovery charge       | $Q_{rr}$       | -      | 0    | -    | nC    | $I_{SD} = 3$ A; $V_{DS} = 400$ V |
| Reverse recovery time         | $t_{rr}$       | -      | 0    | -    | ns    |                                  |
| Peak reverse recovery current | $I_{rrm}$      | -      | 0    | -    | A     |                                  |



## Electrical characteristics diagrams

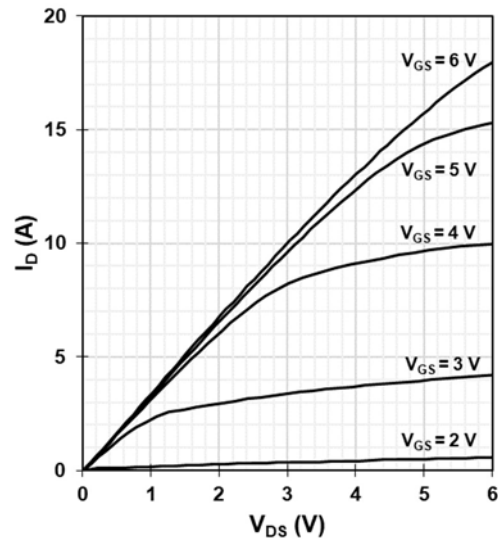
at  $T_j = 25\text{ }^\circ\text{C}$ , unless specified otherwise.

Figure 1 Typ. output characteristics



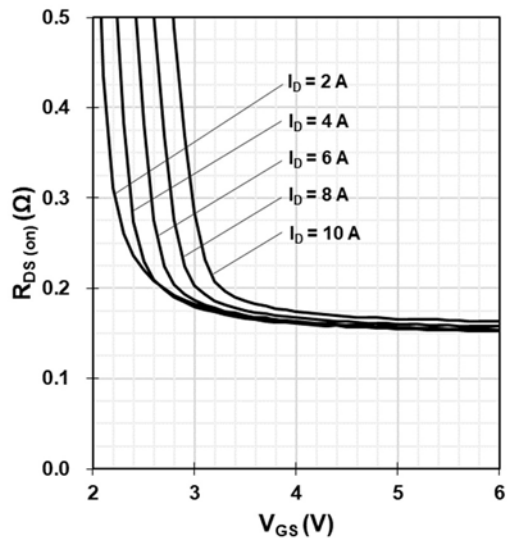
$$I_D = f(V_{DS}, V_{GS}); T_j = 25\text{ }^\circ\text{C}$$

Figure 2 Typ. output characteristics



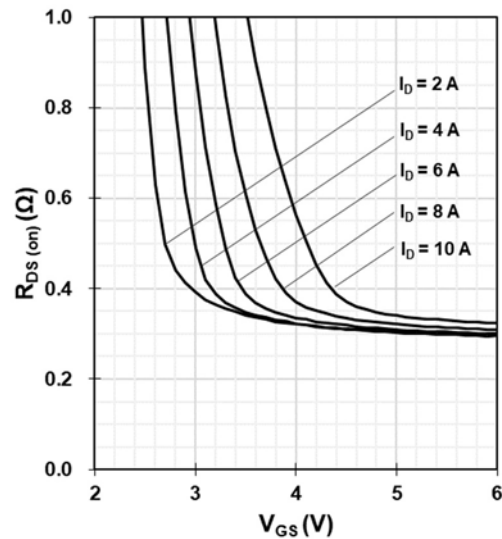
$$I_D = f(V_{DS}, V_{GS}); T_j = 125\text{ }^\circ\text{C}$$

Figure 3 Typ. drain-source on-state resistance



$$R_{DS(on)} = f(I_{DS}, V_{GS}); T_j = 25\text{ }^\circ\text{C}$$

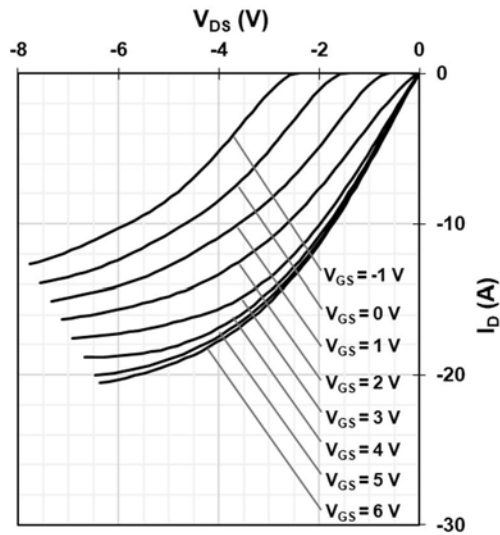
Figure 4 Typ. drain-source on-state resistance



$$R_{DS(on)} = f(I_{DS}, V_{GS}); T_j = 125\text{ }^\circ\text{C}$$

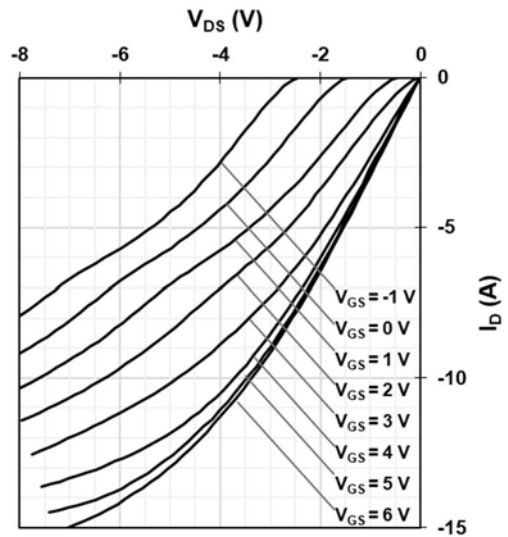


Figure 5 Typ. channel reverse characteristics



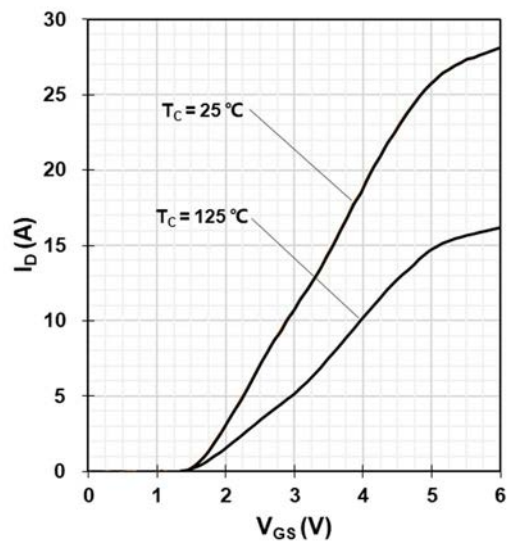
$$I_D = f(V_{DS}, V_{GS}); T_J = 25\text{ }^\circ\text{C}$$

Figure 6 Typ. channel reverse characteristics



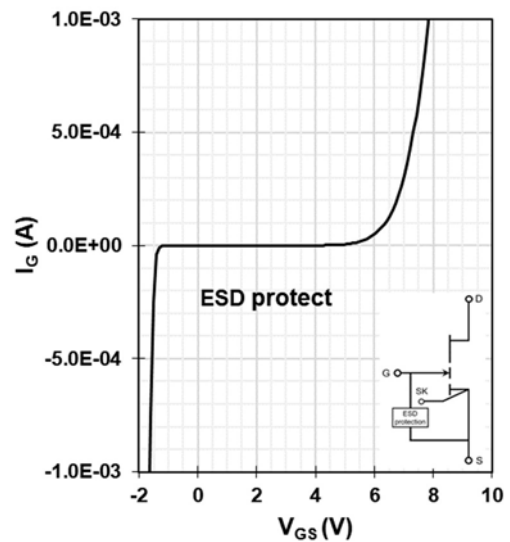
$$I_D = f(V_{DS}, V_{GS}); T_J = 125\text{ }^\circ\text{C}$$

Figure 7 Typ. transfer characteristics



$$I_D = f(V_{GS}); V_{DS} = 5\text{ V}$$

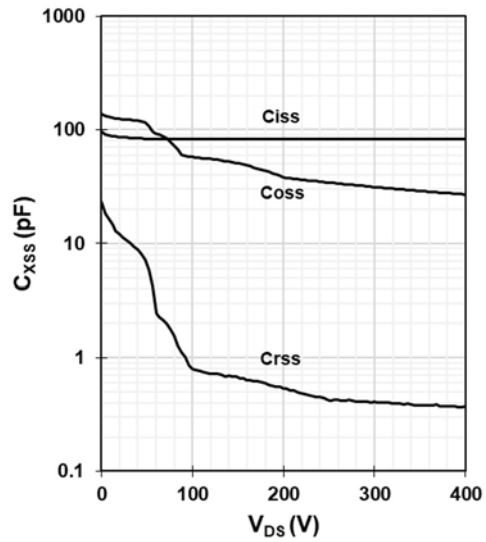
Figure 8 Typ. gate-to-source leakage



$$I_G = f(V_{GS}); I_G \text{ reverse turn on by ESD unit; } V_D = \text{open}$$

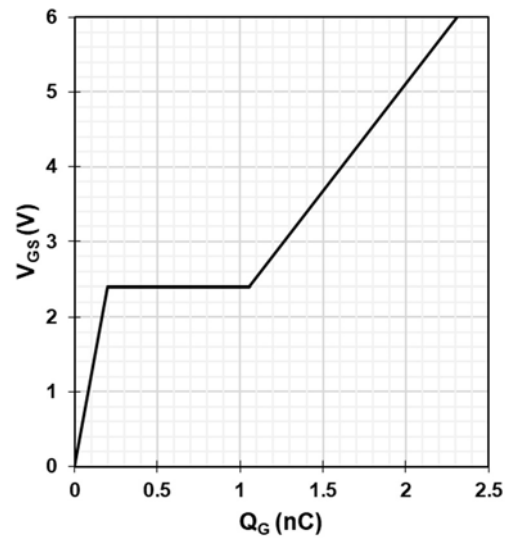


Figure 9 Typ. capacitances



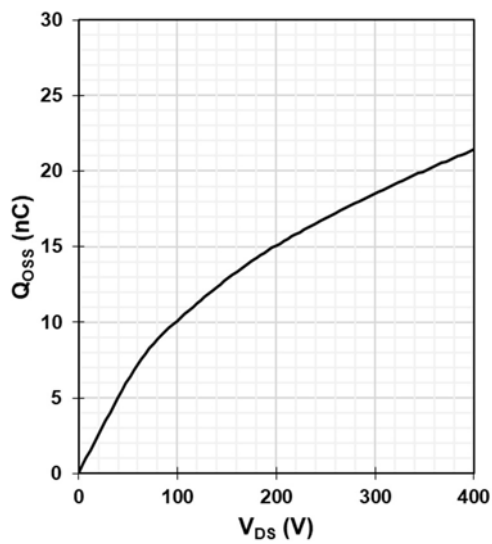
$C_{XSS} = f(V_{DS})$ ; Freq. = 100 kHz

Figure 10 Typ. gate charge



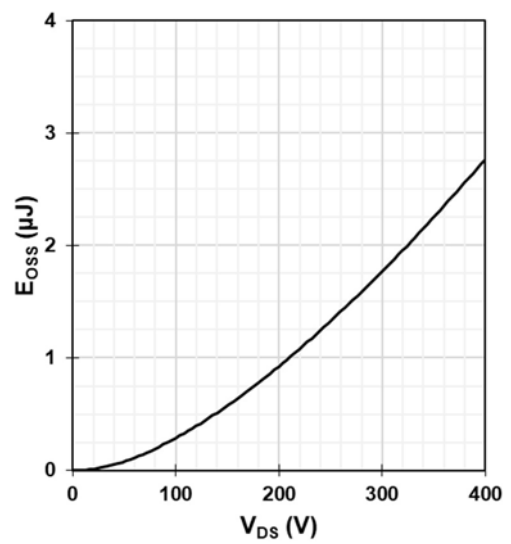
$V_{GS} = f(Q_G)$ ;  $V_{DC-LINK} = 400$  V;  $I_D = 3$  A

Figure 11 Typ. output charge



$Q_{OSS} = f(V_{DS})$ ; Freq. = 100 kHz

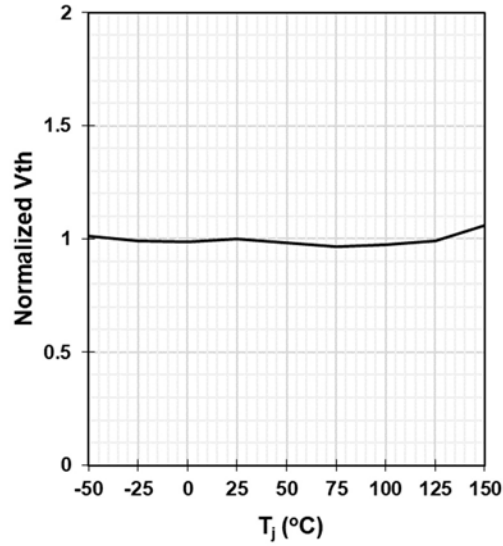
Figure 12 Typ. Coss stored energy



$E_{OSS} = f(V_{DS})$ ; Freq. = 100 kHz

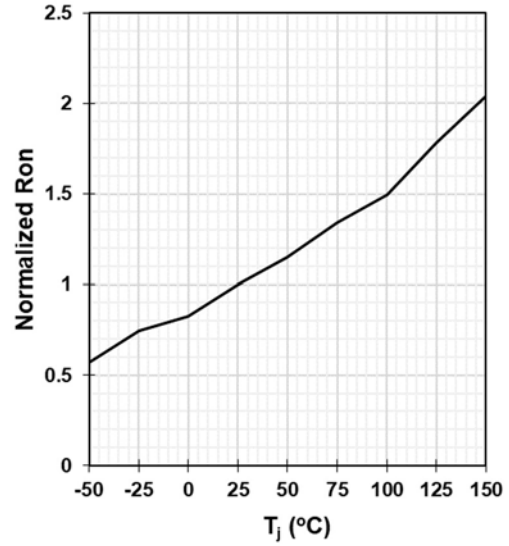


Figure 13 Gate threshold voltage



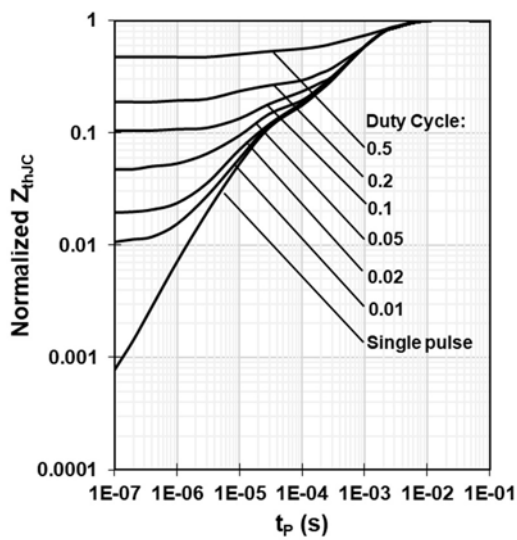
$V_{TH} = f(T_j); V_{GS} = V_{DS}; I_D = 11 \text{ mA}$

Figure 14 Drain-source on-state resistance



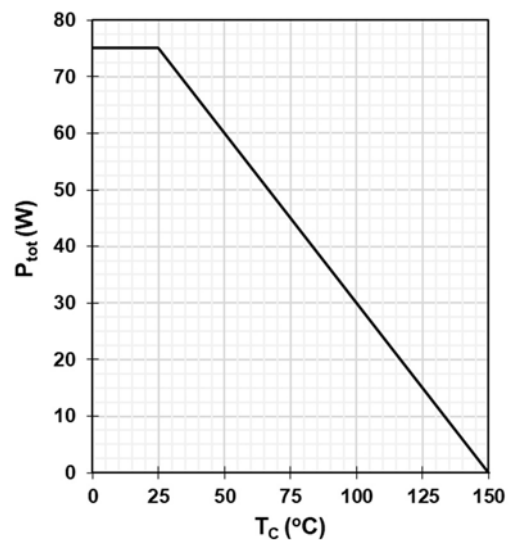
$R_{DS(on)} = f(T_j); I_D = 3 \text{ A}; V_{GS} = 6 \text{ V}$

Figure 15 Max. transient thermal impedance



$Z_{thJC} = f(t_p, D)$

Figure 16 Power dissipation

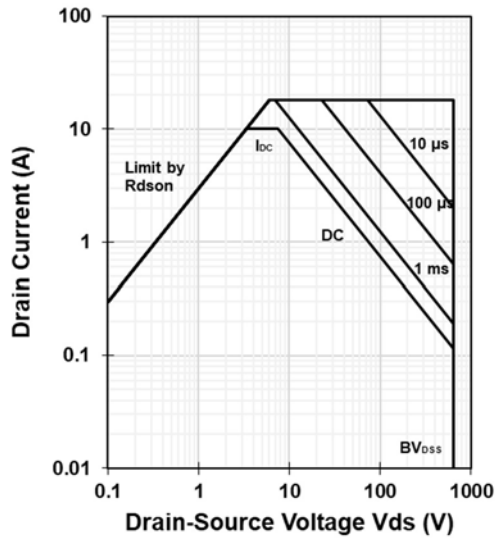


$P_{tot} = f(T_c)$



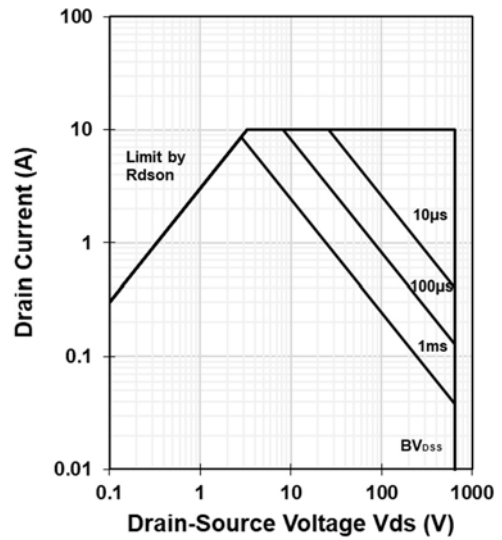


Figure 17 Safe operating area



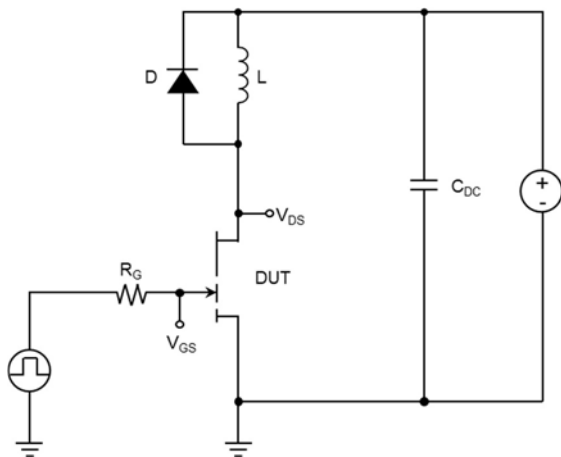
$I_D = f(V_{DS}); T_C = 25\text{ }^\circ\text{C}$

Figure 18 Safe operating area



$I_D = f(V_{DS}); T_C = 125\text{ }^\circ\text{C}$

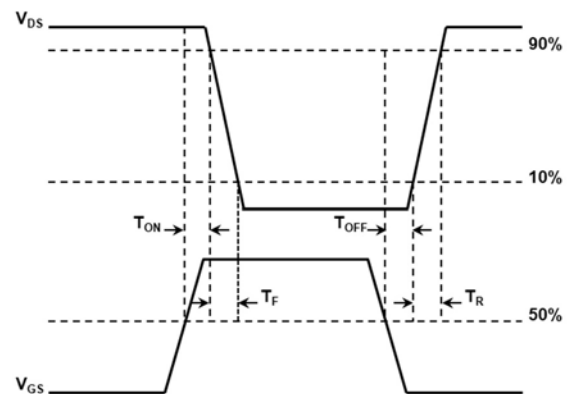
Figure 19 Max. transient thermal impedance



$V_{DS} = 400\text{ V}, I_D = 6\text{ A}, L = 318\text{ }\mu\text{H}, V_{GS} = 6\text{ V},$

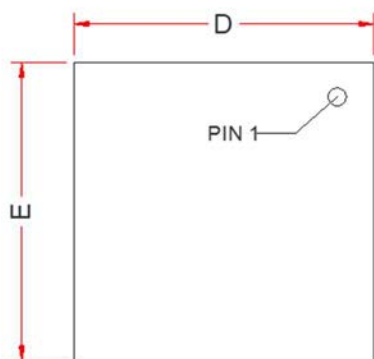
$R_{on} = 10\text{ }\Omega, R_{off} = 2\text{ }\Omega$

Figure 20 Typ. switching times waveform

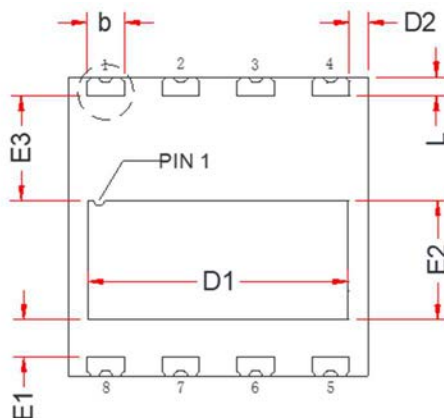




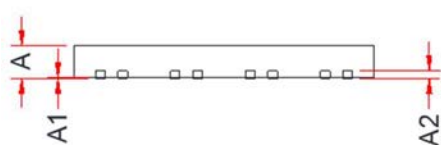
## Package outlines



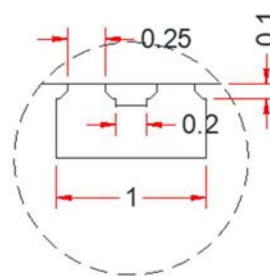
TOP VIEW



BOTTOM VIEW



SIDE VIEW

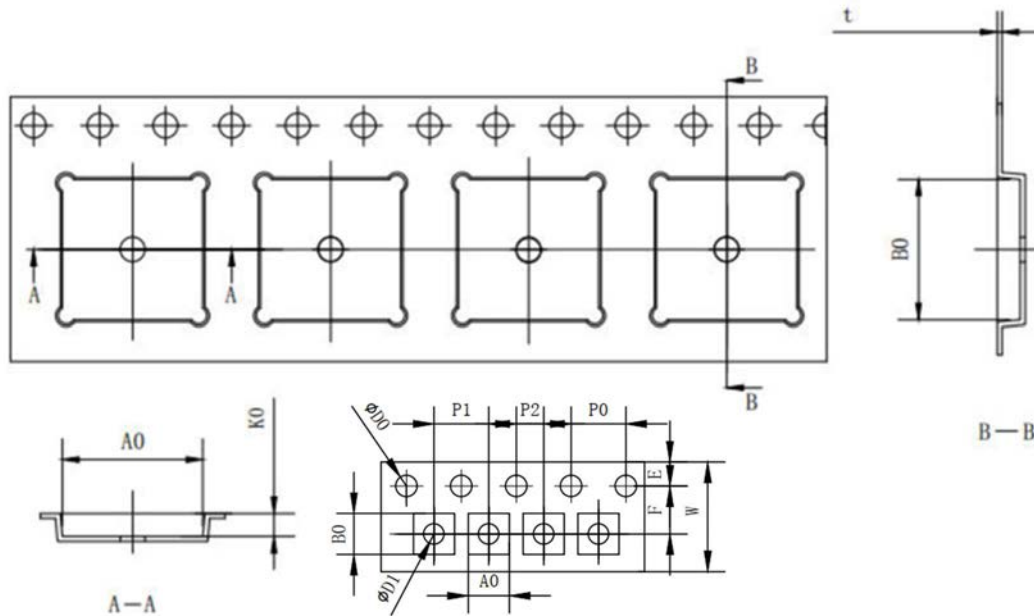


LEAD DETAIL

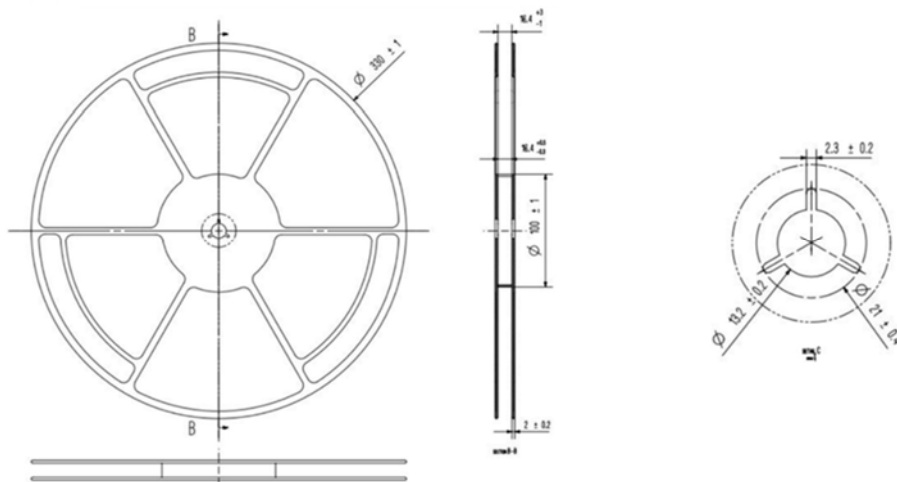
|    | MIN      | MID  | MAX  |
|----|----------|------|------|
| A  | 0.75     | 0.85 | 0.95 |
| A1 | 0.00     | 0.02 | 0.05 |
| A2 | 0.203REF |      |      |
| b  | 0.95     | 1.00 | 1.05 |
| D  | 8.00BSC  |      |      |
| D1 | 6.84     | 6.94 | 7.04 |
| D2 | 0.40     | 0.50 | 0.60 |
| E  | 8.00BSC  |      |      |
| E1 | 0.90     | 1.00 | 1.10 |
| E2 | 3.10     | 3.20 | 3.30 |
| E3 | 2.70     | 2.80 | 2.90 |
| e  | 2.00BSC  |      |      |
| L  | 0.40     | 0.50 | 0.60 |



## Reel information



| SYMBOL | DIMENSION  | SYMBOL | DIMENSION  |
|--------|------------|--------|------------|
| W      | 16.00±0.30 | 10P0   | 40.00±0.20 |
| E      | 1.75±0.10  | P1     | 12.00±0.10 |
| F      | 7.50±0.10  | A0     | 8.30±0.10  |
| D0     | 1.50±0.10  | B0     | 8.30±0.10  |
| D1     | 1.50±0.10  | K0     | 1.10±0.10  |
| P0     | 4.00±0.10  | T      | 0.30±0.05  |
| P2     | 2.00±0.10  |        |            |





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